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July 2014



FDD2572 / FDU2572

N-Channel PowerTrench® MOSFET 150V, 29A, 54m Ω

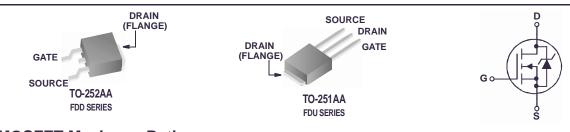
Features

- $r_{DS(ON)} = 45m\Omega$ (Typ.), $V_{GS} = 10V$, $I_D = 9A$
- $Q_q(tot) = 26nC (Typ.), V_{GS} = 10V$
- · Low Miller Charge
- Low RR Body Diode
- UIS Capability (Single Pulse and Repetitive Pulse)

Applications

- DC/DC converters and Off-Line UPS
- · Distributed Power Architectures and VRMs
- Primary Switch for 24V and 48V Systems
- · High Voltage Synchronous Rectifier

Formerly developmental type 82860



MOSFET Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units
V _{DSS}	Drain to Source Voltage	150	V
V _{GS}	Gate to Source Voltage	±20	V
	Drain Current		
I _D	Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 10V$)	29	Α
	Continuous (T _C = 100°C, V _{GS} = 10V)	20	А
	Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} = 10V$, $R_{\theta JA} = 52^{\circ}C/W$)	4	
	Pulsed	Figure 4	А
E _{AS}	Single Pulse Avalanche Energy (Note 1)	36	mJ
P _D	Power dissipation	135	W
	Derate above 25°C	0.9	W/°C
T _J , T _{STG}	Operating and Storage Temperature	-55 to 175	°C

Thermal Characteristics

	1		
$R_{\theta JC}$	Thermal Resistance Junction to Case TO-251, TO-252	1.11	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-251, TO-252	100	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-252, 1in ² copper pad area	52	°C/W

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD2572	FDD2572	TO-252AA	330mm	16mm	2500 units
FDU2572	FDU2572	TO-251AA	Tube	N/A	75 units

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

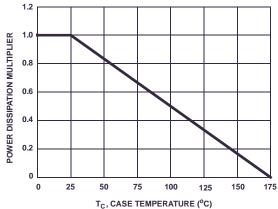
Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
Off Chara	cteristics						
B _{VDSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$		150	-	-	V
		V _{DS} = 120V		-	-	1	
I _{DSS}	Zero Gate Voltage Drain Current	$V_{GS} = 0V$	$T_{\rm C} = 150^{\rm o}$	-	-	250	μΑ
I _{GSS}	Gate to Source Leakage Current	V _{GS} = ±20V		-	-	±100	nA
On Chara	cteristics						
V _{GS(TH)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D =$	250μΑ	2	-	4	V
()		I _D =9A, V _{GS} =10V			0.045	0.054	
r _{DS(ON)}	Drain to Source On Resistance	$I_D = 4A, V_{GS} = 6$	V,	-	0.050	0.075	Ω
- (-)		I _D =9A, V _{GS} =10V	′, T _C =175°C	-	0.126	0.146	
Cliss	Input Capacitance	V _{DS} = 25V, V _{GS}	-V _{DS} = 25V, V _{GS} = 0V,		1770	-	pF
C _{ISS}	Input Capacitance		-V _{DS} = 25V, V _{GS} = 0V, -f = 1MHz		1770	-	pF
C _{OSS}	Output Capacitance				183	-	pF
C _{RSS}	Reverse Transfer Capacitance	2/ 22/			40	-	pF
Q _{g(TOT)}	Total Gate Charge at 10V	$V_{GS} = 0V \text{ to } 10V$		-	26	34	nC
Q _{g(TH)}	Threshold Gate Charge	V _{GS} = 0V to 2V		-	3.3	4.3	nC
Q _{gs}	Gate to Source Gate Charge		$I_D = 9A$ $I_a = 1.0 \text{mA}$	-	8	-	nC
Q _{gs2}	Gate Charge Threshold to Plateau		ig = 1.0mA	-	5	-	nC
Q _{gd}	Gate to Drain "Miller" Charge				6	-	nC
Resistive	Switching Characteristics (V _G	_S = 10V)					
t _{ON}	Turn-On Time			-	-	36	ns
t _{d(ON)}	Turn-On Delay Time	$V_{DD} = 75V, I_{D} = 9A$ $V_{GS} = 10V, R_{GS} = 11.0\Omega$		-	11	-	ns
t _r	Rise Time			-	14	-	ns
t _{d(OFF)}	Turn-Off Delay Time			-	31	-	ns
t _f	Fall Time			-	14	-	ns
t _{OFF}	Turn-Off Time					-	

Drain-Source Diode Characteristics

\/	Source to Drain Diode Voltage	I _{SD} = 9A	-	-	1.25	V
v _{SD}		I _{SD} = 4A	-	-	1.0	V
t _{rr}	Reverse Recovery Time	$I_{SD} = 9A, dI_{SD}/dt = 100A/\mu s$	-	-	74	ns
Q _{RR}	Reverse Recovered Charge	$I_{SD} = 9A, dI_{SD}/dt = 100A/\mu s$	-	-	169	nC

Notes: 1: Starting $T_J = 25^{\circ}C$, L = 0.2mH, $I_{AS} = 19A$.





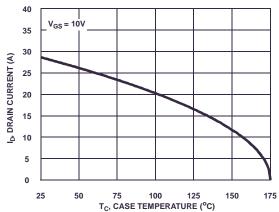


Figure 1. Normalized Power Dissipation vs Ambient Temperature

Figure 2. Maximum Continuous Drain Current vs Case Temperature

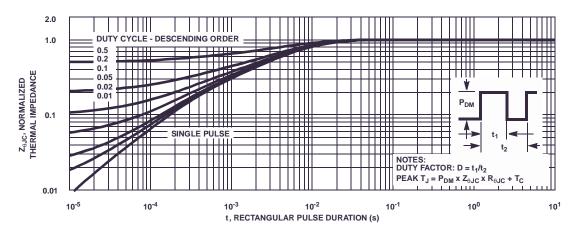


Figure 3. Normalized Maximum Transient Thermal Impedance

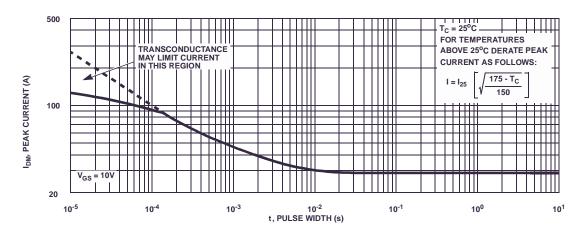


Figure 4. Peak Current Capability

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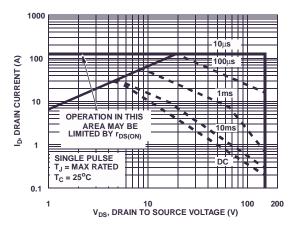
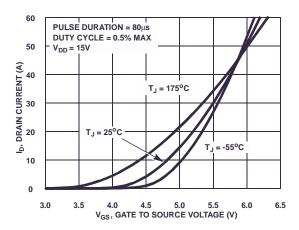


Figure 5. Forward Bias Safe Operating Area

NOTE: Refer to Fairchild Application Notes AN7514 and AN7515

Figure 6. Unclamped Inductive Switching

Capability



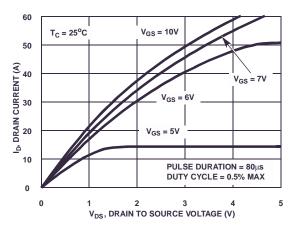
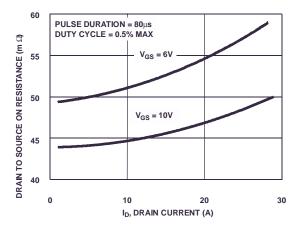


Figure 7. Transfer Characteristics

Figure 8. Saturation Characteristics



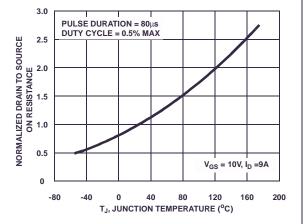


Figure 9. Drain to Source On Resistance vs Drain Current

Figure 10. Normalized Drain to Source On Resistance vs Junction Temperature



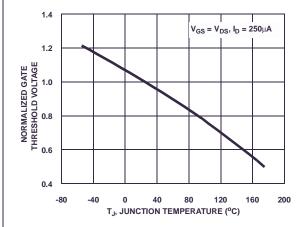
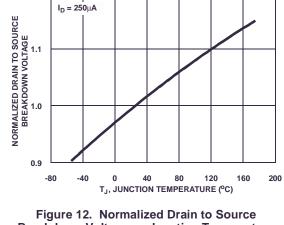


Figure 11. Normalized Gate Threshold Voltage vs **Junction Temperature**



1.2

Breakdown Voltage vs Junction Temperature

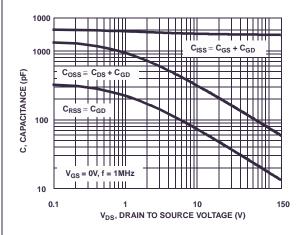


Figure 13. Capacitance vs Drain to Source Voltage

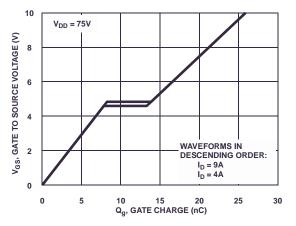
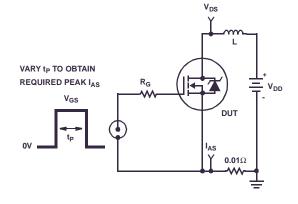


Figure 14. Gate Charge Waveforms for Constant **Gate Currents**

Test Circuits and Waveforms



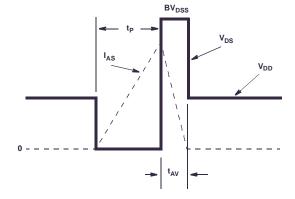


Figure 15. Unclamped Energy Test Circuit

Figure 16. Unclamped Energy Waveforms

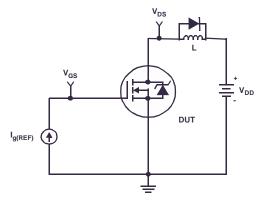


Figure 17. Gate Charge Test Circuit

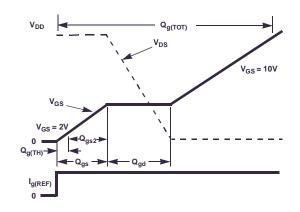


Figure 18. Gate Charge Waveforms

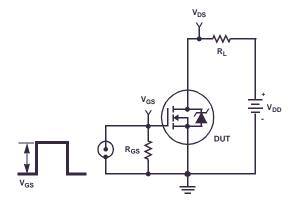


Figure 19. Switching Time Test Circuit

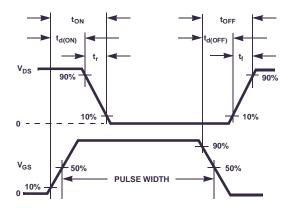


Figure 20. Switching Time Waveforms

Thermal Resistance vs. Mounting Pad Area

The max imum r ated j unction t emperature, T $_{JM}$, an d t he thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P $_{DM}$, in an application. T herefore the application's ambient temperature, T $_{A}$ (°C), and thermal resistance R $_{\theta JA}$ (°C/W) must be reviewed to ensure that T $_{JM}$ is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}} \tag{EQ. 1}$$

In us ing su rface mount de vices suc h as t he TO-252 package, the environment in which it is applied will have a significant in fluence o n t he p art's cur rent and max imum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- For no n s teady st ate applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild p rovides t hermal information to as sist t he designer's preliminary ap plication ev aluation. F igure 21 defines the R $_{\theta JA}$ for the device as a function of the top copper (component si de) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be ev aluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

Thermal resistances co rresponding to other copper areas can be obtained from F igure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeter square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\theta JA} = 33.32 + \frac{23.84}{(0.268 + Area)}$$
 (EQ. 2)

Area in Inches Squared

$$R_{\Theta JA} = 33.32 + \frac{154}{(1.73 + Area)}$$
 (EQ. 3)

Area in Centimeters Squared

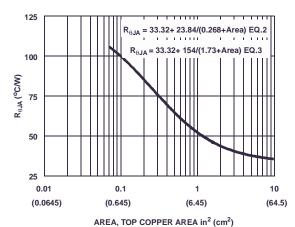
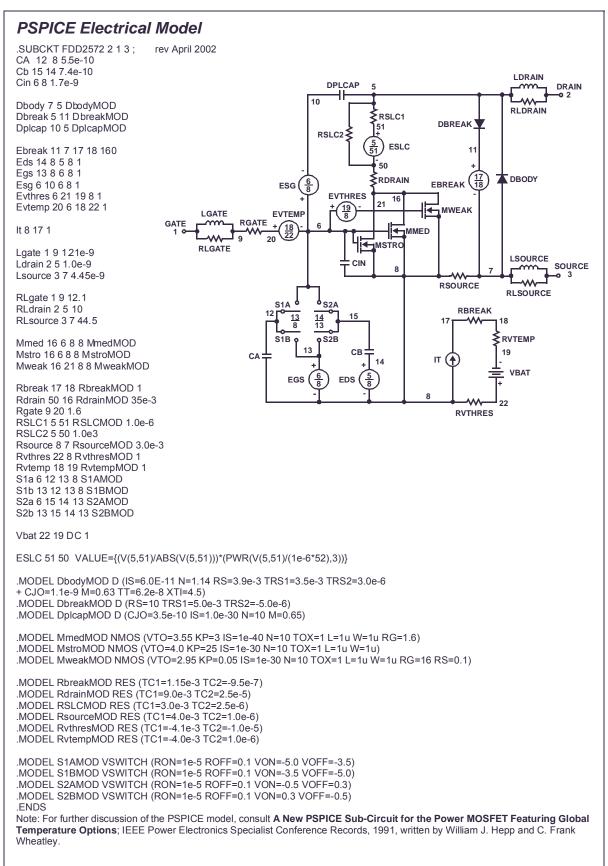
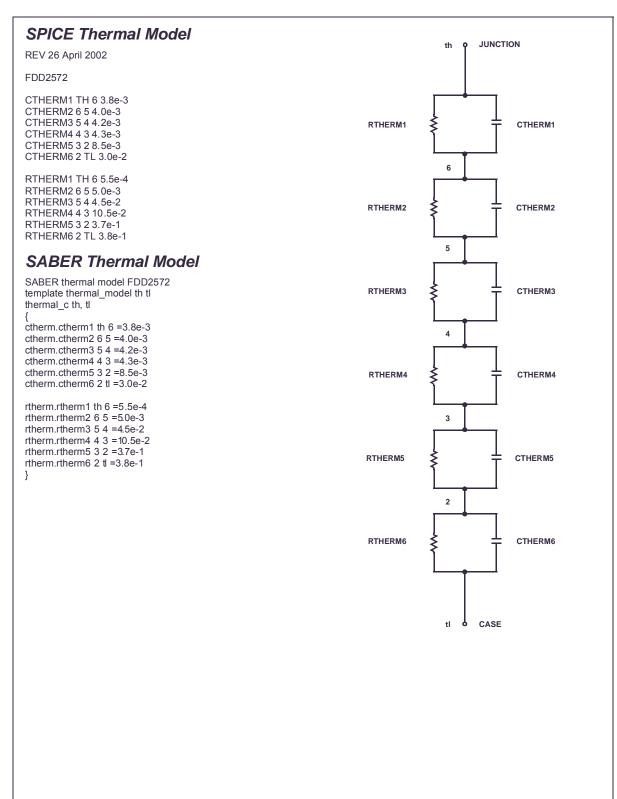


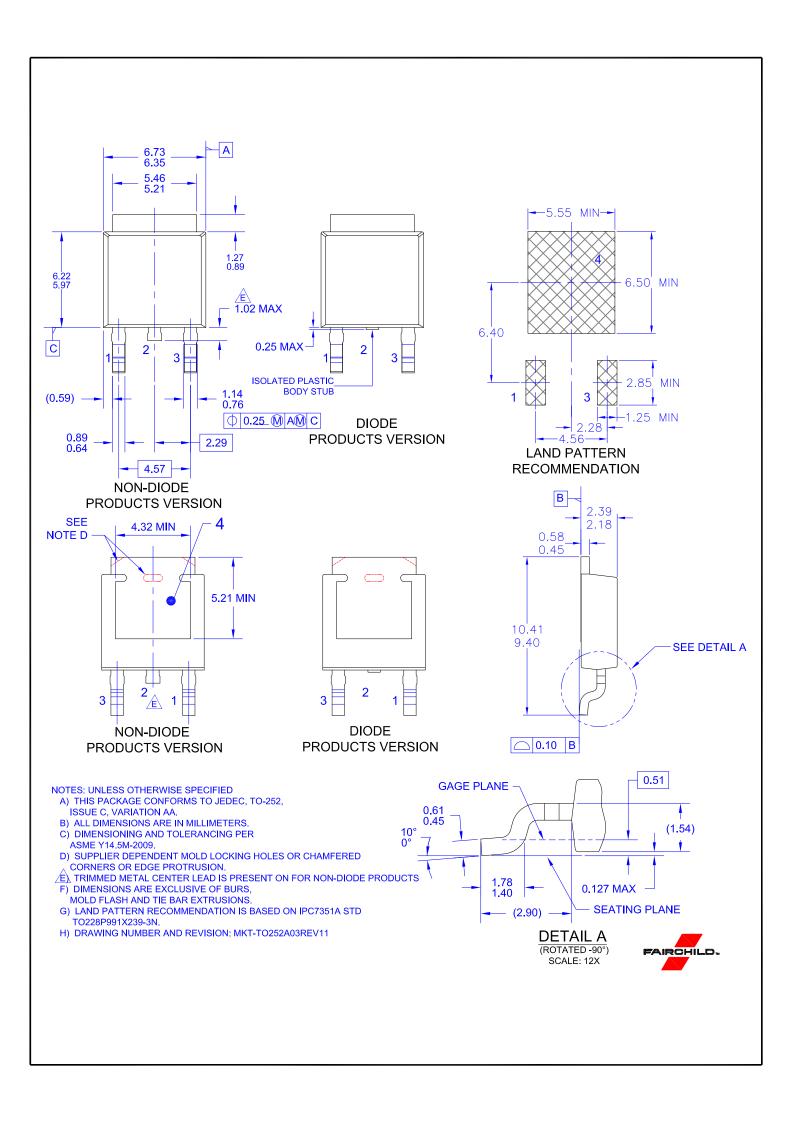
Figure 21. Thermal Resistance vs Mounting
Pad Area



SABER Electrical Model REV April 2002 ttemplate FDD2572 n2,n1,n3 electrical n2,n1,n3 var i iscl dp..model dbodymod = (isl=6.0e-11,nl=1.14,rs=3.9e-3,trs1=3.5e-3,trs2=3.0e-6,cjo=1.1e-9,m=0.63,tt=6.2e-8,xti=4.5) dp..model dbreakmod = (rs=10.trs1=5.0e-3.trs2=-5.0e-6) dp..model dplcapmod = (cjo=3.5e-10,isl=10.0e-30,nl=10,m=0.65) m..model mmedmod = (type=_n,vto=3.55,kp=3,is=1e-40, tox=1) m..model mstrongmod = $(type=_n, vto=4.0, kp=25, is=1e-30, tox=1)$ m..model mstroriginiou – (type=_ii,vio==x,o,np=zo,io io co, cox = 1,rs=0.1) m..model mweakmod = (type=_n,vto=2.95,kp=0.05,is=1e-30, tox=1,rs=0.1) **LDRAIN** DRAIN sw_vcsp..model s1amod = (ron=1e-5,roff=0.1,von=-5.0,voff=-3.5) sw_vcsp..model s1bmod = (ron=1e-5,roff=0.1,von=-3.5,voff=-5.0) 10 RLDRAIN sw_vcsp..model s2amod = (ron=1e-5,roff=0.1,von=-0.5,voff=0.3) **≨**RSLC1 sw_vcsp..model s2bmod = (ron=1e-5,roff=0.1,von=0.3,voff=-0.5) RSLC2 ≸ c.ca n12 n8 = 5.5e-10 c.cb n15 n14 = 7.4e-10 ISCI c.cin n6 n8 = 1.7e-9 DBREAK 3 50 dp.dbody n7 n5 = model=dbodymod **≷**RDRAIN 8 FSG (11 dp.dbreak n5 n11 = model=dbreakmod DBODY **FVTHRES** dp.dplcap n10 n5 = model=dplcapmod MWFAK LGATE **EVTEMP** RGATE spe.ebreak n11 n7 n17 n18 = 160 GATE 18 22 **←**MMED spe.eds n14 n8 n5 n8 = 1 20 **←** MSTR spe.egs n13 n8 n6 n8 = 1 RLGATE spe.esg n6 n10 n6 n8 = 1 **LSOURCE** CIN SOURCE spe.evthres n6 n21 n19 n8 = 1 spe.evtemp n20 n6 n18 n22 = 1 RSOURCE RLSOURCE i.it n8 n17 = 1RBREAK <u>14</u> 13 I.lgate n1 n9 = 1.21e-9I.ldrain n2 n5 = 1.0e-9RVTEMP S₁B oS2B I.lsource n3 n7 = 4.45e-9СВ 19 14 res.rlgate n1 n9 = 12.1 VBAT EGS EDS res.rldrain n2 n5 = 10 res.rlsource n3 n7 = 44.5 **RVTHRES** m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u m.mweak n16 n21 n8 n8 = model=mweakmod, I=1u, w=1u res.rbreak n17 n18 = 1, tc1=1.15e-3,tc2=-9.5e-7 res.rdrain n50 n16 = 35e-3, tc1=9.0e-3,tc2=2.5e-5 res.rgate n9 n20 = 1.6 res.rslc1 n5 n51 = 1.0e-6, tc1=3.0e-3,tc2=2.5e-6 res.rslc2 n5 n50 = 1.0e3 res.rsource n8 n7 = 3.0e-3, tc1=4.0e-3,tc2=1.0e-6 res.rvthres n22 n8 = 1, tc1=-4.1e-3,tc2=-1.0e-5 res.rvtemp n18 n19 = 1, tc1=-4.0e-3,tc2=1.0e-6 sw vcsp.s1a n6 n12 n13 n8 = model=s1amod sw vcsp.s1b n13 n12 n13 n8 = model=s1bmod sw_vcsp.s2a n6 n15 n14 n13 = model=s2amod sw_vcsp.s2b n13 n15 n14 n13 = model=s2bmod v.vbat n22 n19 = dc=1 equations { i (n51->n50) +=iscl |sc| = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))*((abs(v(n5,n51)*1e6/52))**3))

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